

wherein  $(p_{j,n} - p_{\text{initial},j,n})$  represents the trace with the difference between the calculated subsurface parameter  $n$  at trace position  $j$  and the corresponding initial subsurface parameter,  $w_{\text{initial},n}$  is a weighting factor for the  $n^{\text{th}}$  parameter,  $\# \text{traces}$  is the total number of traces,  $\# \text{parameters}$  is the number of parameters and  $L_{P,\text{initial}}$  is an adjustable norm of said difference.

8 10. (Original) The method according to claim 7, wherein a stabilization term is a measure for the deviation of the calculated subsurface parameters from a priori specified functional relationships between subsurface parameters.

9 11. (Original) The method according to claim 10, wherein said measure comprises

$$F_{\text{functions}} = \sum_{v=1}^{\# \text{ functions}} w_{\text{functions},v} \sum_{j=1}^{\# \text{ traces}} L_{P,\text{functions}} f_v(p_j, \dots, p_j, \# \text{ parameters})$$

wherein  $f_v$  represents the deviations of the subsurface parameters at trace  $j$  away from the  $v^{\text{th}}$  functional relationship between different subsurface parameters,  $w_{\text{functions},v}$  is a weighting function for the  $v^{\text{th}}$  functional relationship,  $\# \text{traces}$  is the number of traces,  $\# \text{functions}$  is the number of functional relations and  $L_{P,\text{functions}}$  is an adjustable norm of said deviations.

12. (Original) The method according to claim 3, wherein a stabilization

term is a measure for the lateral variability of the parameters.

13.

(Original)

The method according to claim 12, wherein said measure

comprises

$$F_{lateral} = \sum_{n=1}^{\#parameters} \sum_{l=1}^{\#neighbors} \sum_{j=1}^{\#traces} w_{lateral,n}(r_{j,l}) L_{P,lateral}(d_{j,l,n})$$

wherein  $d_{j,n,l}$  is the difference of the samples of parameter  $p_n$  at traces  $j$  and  $l$ , corrected with any difference in the initial model,  $w_{lateral,n}(\tau_{j,l})$  is a trace for parameter  $n$  describing the weighting for each parameter sample where this weighting is a function of  $\tau_{j,l}$  which is a trace which at each parameter sample provides a measure of the local correlation between the traces  $j$  and  $l$ ,  $\#traces$  is the number of traces,  $\#neighbors$  is the number of neighboring traces used in the calculation,  $\#parameters$  is the number of parameters and  $L_{p,lateral}$  is the adjustable norm of said differences  $d_{j,n,l}$ .

14.

(Original)

The method according to claim 13, wherein the parameter

difference  $d_{j,l,n}$  is defined as

$$(d_{j,l,n})(t_k) = p_{l,n}(t_k + \Delta t_{j,l,k}) - p_{j,n}(t_k) - (p_{initial,l,n}(t_k + \Delta t_{j,l,k}) - p_{initial,j,n}(t_k))$$

wherein  $\Delta t_{j,l,k}$  is the time shift at parameter sample  $k$  which time aligns the parameters of trace  $l$  to trace  $j$  at sample  $k$ , where surrounding trace samples are interpolated if at time  $t_k + \Delta t_{j,l,k}$  a

37 35. (Original) The method according to claim 33, wherein the objective function comprises one or more stabilization terms and/or one or more correction terms.

36 36. (Original) The method according to claim 35, wherein a stabilization term is a measure for the deviation of the reflectivity away from 0.

37 37. (Original) The method according to claim 36, wherein said measure comprises

$$F_{\text{reflectivity}} = \sum_{i=1}^{\# \text{stacks}} w_{\text{reflectivity},i} \sum_{j=1}^{\# \text{traces}} L_{P,\text{reflectivity}}(r_{i,j})$$

wherein  $r_{i,j}$  is the reflectivity trace for stack  $i$  and trace  $j$ ,  $w_{\text{reflectivity},i}$  is a weighting factor for stack  $i$ ,  $\# \text{traces}$  is the total number of traces,  $\# \text{stacks}$  is the total number of stacks and  $L_{P,\text{reflectivity}}$  is an adjustable norm of the reflectivities.

40 38. (Original) The method according to claim 35, wherein a stabilization term is a measure for the parameter contrast.

41 39. (Original) The method according to claim 38, wherein said measure comprises

$$F_{\text{contrast}} = \sum_{n=1}^{\# \text{parameters}} w_{\text{contrast},n} \sum_{j=1}^{\# \text{traces}} L_{P,\text{contrast}}(c_{j,n})$$

wherein  $c_{j,n}$  is the contrast trace for the  $n^{\text{th}}$  subsurface parameter,  $w_{\text{contrast},n}$  is a weighting factor for the  $n^{\text{th}}$  parameter,  $\# \text{traces}$  is the total number of traces,  $\# \text{parameters}$  is the number of parameters, and  $L_{P,\text{contrast}}$  is an adjustable norm of the contrasts.

44 40. (Original) The method according to claim 35, wherein a stabilization term is a measure for the deviation of the subsurface parameters from the initial subsurface parameters.

45 41. (Original) The method according to claim 40, wherein said measure comprises

$$F_{\text{initial}} = \sum_{n=1}^{\# \text{parameters}} w_{\text{initial},n} \sum_{j=1}^{\# \text{traces}} L_{P,\text{initial}}(p_{j,n} - p_{\text{initial},j,n})$$

wherein  $(p_{j,n} - p_{\text{initial},j,n})$  represents the trace with the difference between the calculated subsurface parameter  $n$  at trace position  $j$  and the corresponding initial subsurface parameter,  $w_{\text{initial},n}$  is a weighting factor for the  $n^{\text{th}}$  parameter,  $\# \text{traces}$  is the total number of traces,  $\# \text{parameters}$  is the number of parameters and  $L_{P,\text{initial}}$  is an adjustable norm of said difference.

42. (Original) The method according to claim <sup>41</sup>39, wherein a stabilization term is a measure for the deviation of the calculated subsurface parameters from a priori specified functional relationships between subsurface parameters.

43. (Original) The method according to claim 42, wherein said measure comprises

$$F_{functions} = \sum_{v=1}^{\# functions} w_{functions,v} \sum_{j=1}^{\# traces} L_{P,functions} f_v(p_{j,1}, \dots, p_{j,\# parameters})$$

wherein  $f_v$  represents the deviations of the subsurface parameters at trace  $j$  away from the  $v^{th}$  functional relationship between different subsurface parameters,  $w_{functions,v}$  is a weighting function for the  $v^{th}$  functional relationship,  $\#traces$  is the number of traces,  $\#functions$  is the number of functional relations and  $L_{P,functions}$  is an adjustable norm of said deviations.

44. (Original) The method according to claim <sup>37</sup>35, wherein a stabilization term is a measure for the lateral variability of the parameters.

45. (Original) The method according to claim <sup>46</sup>44, wherein said measure comprises

$$F_{lateral} = \sum_{n=1}^{\#parameters} \sum_{l=1}^{\#neighbors} \sum_{j=1}^{\#traces} w_{lateral,n}(r_{j,l}) L_{P,lateral}(d_{j,l,n})$$

wherein  $d_{j,n,l}$  is the difference of the samples of parameter  $p_n$  at traces  $j$  and  $l$ , corrected with any difference in the initial model,  $w_{lateral,n}(r_{j,l})$  is a trace for parameter  $n$  describing the weighting for each parameter sample where this weighting is a function of  $r_{j,l}$  which is a trace which at each parameter sample provides a measure of the local correlation between the traces  $j$  and  $l$ ,  $\#traces$  is the number of traces,  $\#neighbors$  is the number of neighboring traces used in the calculation,  $\#parameters$  is the number of parameters and  $L_{P,lateral}$  is the adjustable norm of said differences  $d_{j,n,l}$ .

47

48-46 (Original) The method according to claim 45, wherein the parameter difference  $d_{j,l,n}$  is defined as

$$(d_{j,l,n})(t_k) = p_{l,n}(t_k + \Delta t_{j,l,k}) - p_{j,n}(t_k) - (p_{initial,l,n}(t_k + \Delta t_{j,l,k}) - p_{initial,j,n}(t_k))$$

wherein  $\Delta t_{j,l,k}$  is the time shift at parameter sample  $k$  which time aligns the parameters of trace  $l$  to trace  $j$  at sample  $k$ , where surrounding trace samples are interpolated if at time  $t_k + \Delta t_{j,l,k}$  a sample is not defined, where  $r_{j,l}$  is now the local correlation incorporating the time shift and  $L_{P,lateral}$  is an adjustable norm on the parameter differences.

50-47. (Original) The method according to claim 33, wherein a correction term is a measure for the differential time shifts between traces of measured reflection data

stacks.

50

(51) 48. (Original) The method according to claim 47, wherein said measure comprises

$$F_{time} = \sum_{i=2}^{\#stacks} w_{time,i} \sum_{j=1}^{\#traces} L_{P,time}(\tau_{ij} - \tau_{0,ij})$$

wherein  $\tau_{0,ij}$  is the trace with the initial time values of the time stretch and squeeze control points for stack  $i$  and trace  $j$  and  $\tau_{ij}$  is the time of shifted control points,  $w_{time,i}$  is a weighting factor for stack  $i$ ,  $\#stacks$  is the number of stacks,  $\#traces$  is the number of traces and  $L_{P,time}$  is an adjustable normalization factor of the difference between  $\tau_{0,ij}$  and  $\tau_{ij}$ .

(52) 49. (Original) The method according to claim 33, wherein a stabilization term is a measure for the parameter differences between reflection data acquisition surveys taken at different points in time.

52

(53) 50. (Original) The method according to claim 49, wherein said measure comprises

$$F_{timelapse} = \sum_{k=2}^{\#surveys} w_{survey,k} \sum_{n=1}^{\#parameters} w_{parameters,n} \sum_{j=1}^{\#traces} L_{P,timelapse}(p_{j,n,k} - p_{j,n,k-1})$$

49 63. (Original) The method according to claim <sup>37</sup>~~35~~, wherein the seismic reflection data is determined from at least one of the following source-receiver combinations:

P-wave source and P-wave receiver, P-wave source and S-wave receiver, S-wave source and P-wave receiver, S-wave source and S-wave receiver.

64. (Original) The method according to claim 33, wherein the reflection data is echo-acoustic data and the subsurface is human or mammal tissue or any other material.

65. (Currently Amended) A device for determining from measured reflection data on a plurality of trace positions one or more subsurface parameters, the device comprising:

(a) input means for inputting at least the measured reflection data and one or more initial subsurface parameters defining an initial subsurface model;

(b) processing means for:

(i) preprocessing the measured reflection data into a plurality of partial or full stacks;

(ii) specifying a wavelet or wavelet or wavelet field for each of the partial or full stacks of the measured reflection data;

(iii) calculating synthetic reflection data based on the specified wavelets or wavelet fields and the initial subsurface parameters; and